

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251810US2	SERIAL NO. 10/828,322 New Application		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Takahiro NAKAMOTO					
		FILING DATE Herewith	04/21/2004	GROUP 2815			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>Dale</i>	AA	6,057,566	05/02/00	Kurt W. EISENBEISER, et al.	257	192	<i> </i>
	AB						
	AC						
	AD						
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	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION <i>CH/PT/EN/DE/ES/FR</i>	YES	NO
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
<i>Dale</i>	AW	R. E. WILLIAMS, et al. "Graded Channel FET's: Improved Linearity and Noise Figure", IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. ED-25, No. 6, June 1978, pgs. 600-605					
<i>Dale</i>	AX	James A. ADAMS, et al. "Short-Channel Effects and Drain-Induced Barrier Lowering in Nanometer-Scale GaAs MESFET's", IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. 40, No. 6, June 1993, pgs. 1047-1052					
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner	<i>Dale</i>					Date Considered <i>5/18/05</i>	

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.